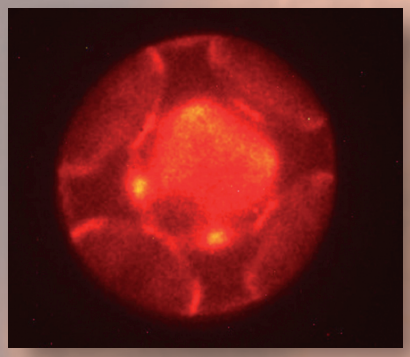
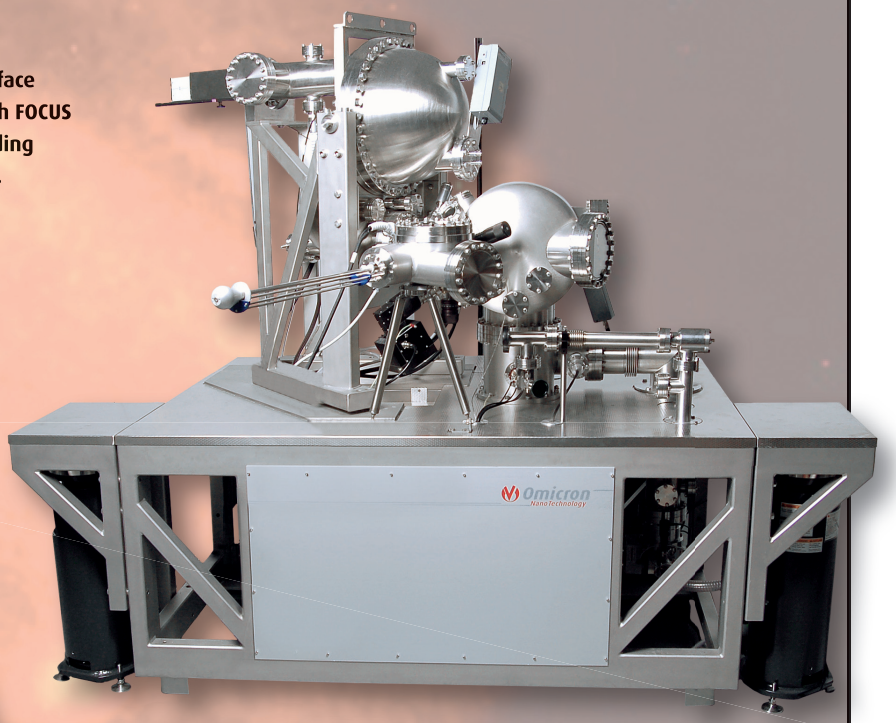
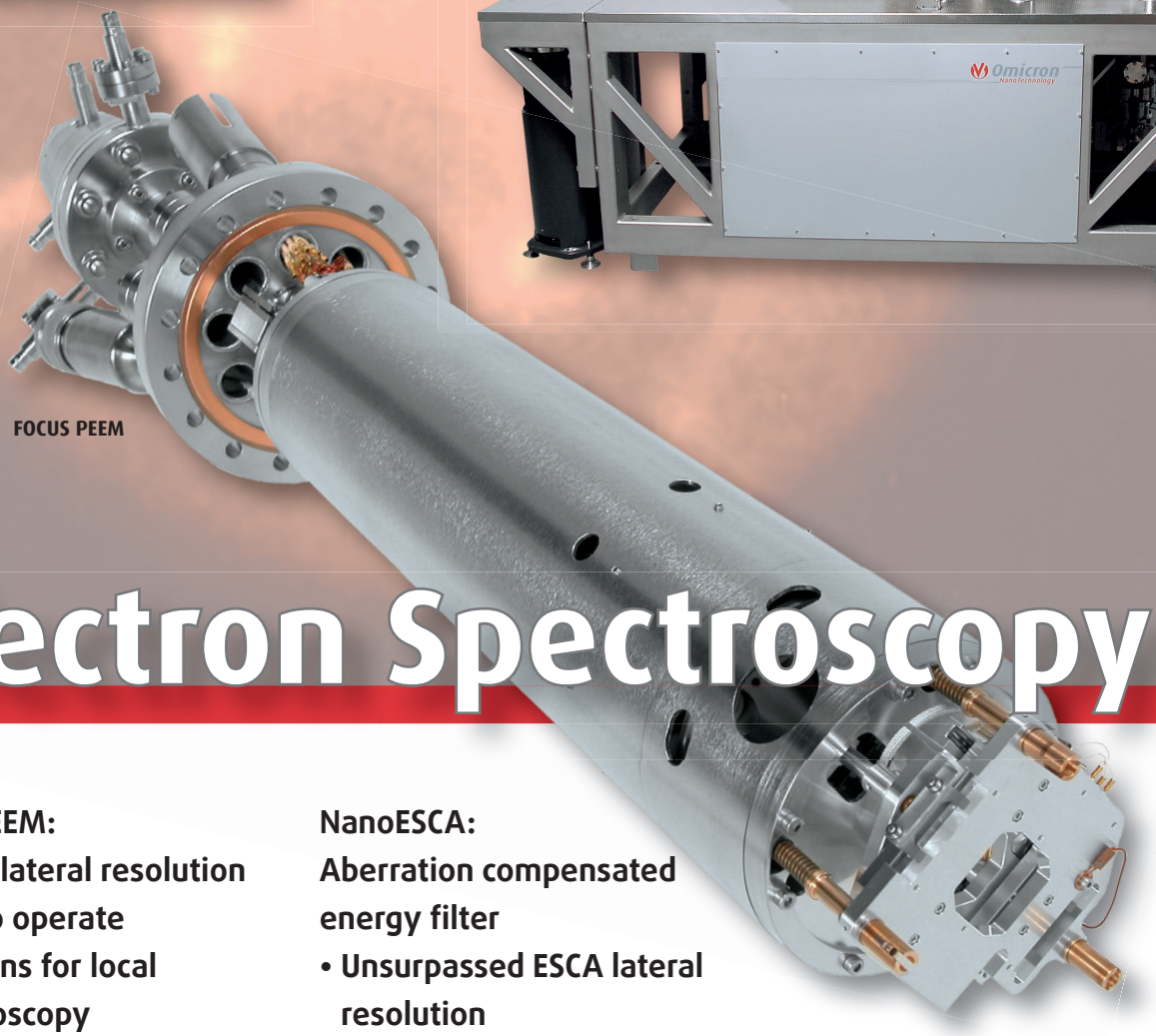
Surface Science Instruments



Ag(100): Fermi surface map measured with FOCUS IS-PEEM with retarding field analyser (IEF).



NanoESCA



FOCUS PEEM

Electron Spectroscopy

Focus PEEM:

- 20 nm lateral resolution
- Easy to operate
- Solutions for local spectroscopy
- Compatible with MULTIPROBE UHV systems

NanoESCA:

Aberration compensated energy filter

- Unsurpassed ESCA lateral resolution
- Fast and controlled switching between real space and k-space

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FOCUS GmbH

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